



Accelerated Environmental Stress Test Summary

Test	#	Reference	Test Conditions	Duration	Lots	Sample Size / lot	Total
PC	1	JESD22-A113 J-STD-020	Preconditioning per Datasheet MSL Moisture Preconditioning + 3x reflow:	Total sample size = 1,155			
HTOL	2	JESD22-A108	High Temperature Operating Life: 125°C / Max Operating V_{DS} / 24V V_{CC} / 350kHz / 50% Duty Cycle	1000hrs	3	77	231
HTRB	3	JESD22-A108	High Temperature Reverse Bias: 125°C / Max Operating V_{DS}	1000hrs	3	77	231
HTGB	4	JESD22-A108	High Temperature Gate Bias: 150°C / 7V V_{GS}	1000hrs	3	77	231
THB	5	JESD22-A101	Temperature Humidity Bias: 85°C / 85%RH / 100V V_{DS}	1000hrs	3	77	231
HAST	6	JESD22-A110	Highly Accelerated Stress Test: 130°C / 85%RH / 100V V_{DS}	96hrs	3	77	231
UHAST	7	JESD22-A118	Unbiased Highly Accelerated Stress Test: 110°C / 85%RH	264hrs	3	77	231
TC	8	JESD22-A104	Temperature Cycle: -55°C / 150°C	1000cy	3	77	231
HTSL	8	JESD22-A103	High Temperature Storage Life: 150°C	1000hrs	3	77	231
ELFR	10	JESD22-A108	Early Life Failure Rate High Temperature Reverse Bias 125°C / Max Operating V_{DS}	168hrs	3	800	2400
SD	11	J-STD-002D	Solderability	N/A	3	5	15
PD	12	SAC-STD-004	Physical Dimensions	N/A	3	10	30
WBS	13	MIL-STD-883	Wire Bond Strength	N/A	3	30	90
BS	14	JESD22-B116	Bond Shear	N/A	3	30	90
DS	15	MIL-STD-883	Die Shear	N/A	3	5	20
HBM	16	JS-001-2014	Human Body Model ESD	3/pin pair			
CDM	17	JS-002-2014	Charged Device Model ESD	3/pin pair			